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MAR 3 1 2006 Docket No. 60417 (71987)

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT:

C. Chen et al.

U.S. SERIAL NO.:

10/728,304

EXAMINER: T. Nguyen

FILED:

December 3, 2003

GROUP:

2829

FOR:

CHIP CARRIER AND METHOD FOR TESTING ELECTRICAL

PERFORMANCE OF PASSIVE COMPONENT

## CERTIFICATE OF FACSIMILE TRANSMISSION

I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being transmitted by facsimile to the U.S. Patent & Trademark Office by facsimile number 571-273-8300 on March 31, 2006.

Steven M. Jensen

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

## RESPONSE TO OFFICE ACTION

Applicants are in receipt of the Office Action dated December 15, 2005 of the abovereferenced application. A request for a one-month extension of time is submitted herewith. Applicants respond to the Office Action as follows.

Applicants' claimed invention is directed to a chip carrier and a method for testing electrical performance of a passive component. As recited in claim 1, at least one first trace has a first predetermined position, and at least one second trace has a second predetermined position, where the first and second predetermined positions are located on the same surface of the chip carrier. Also, a first ball pad and a second ball pad are formed on an opposite surface of the chip carrier.